

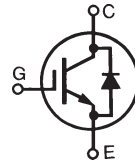
**XPT™ 600V IGBT  
GenX3™ w/Diode**
**MMIX1X200N60B3H1**

$$V_{CES} = 600V$$

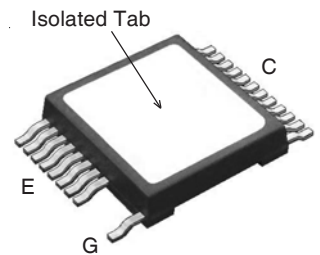
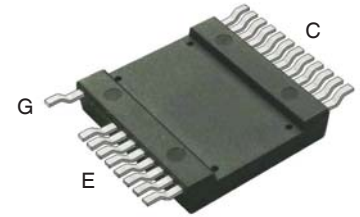
$$I_{C110} = 72A$$

$$V_{CE(sat)} \leq 1.7V$$

$$t_{fi(typ)} = 110ns$$

**(Electrically Isolated Tab)**

 Extreme Light Punch Through  
IGBT for 10-30kHz Switching

| Symbol         | Test Conditions   | Maximum Ratings         |            |
|----------------|---|-------------------------|------------|
| $V_{CES}$      | $T_J = 25^\circ C$ to $150^\circ C$                       | 600                     | V          |
| $V_{CGR}$      | $T_J = 25^\circ C$ to $150^\circ C$ , $R_{GE} = 1M\Omega$ | 600                     | V          |
| $V_{GES}$      | Continuous  | $\pm 20$                | V          |
| $V_{GEM}$      | Transient   | $\pm 30$                | V          |
| $I_{C25}$      | $T_C = 25^\circ C$ (Chip Capability)                      | 175                     | A          |
| $I_{C110}$     | $T_C = 110^\circ C$                                       | 72                      | A          |
| $I_{F110}$     | $T_C = 110^\circ C$                                       | 28                      | A          |
| $I_{CM}$       | $T_C = 25^\circ C$ , 1ms                                  | 1000                    | A          |
| $I_A$          | $T_C = 25^\circ C$  | 100                     | A          |
| $E_{AS}$       | $T_C = 25^\circ C$  | 1                       | J          |
| <b>SSOA</b>    | $V_{GE} = 15V$ , $T_{VJ} = 150^\circ C$ , $R_G = 1\Omega$ | $I_{CM} = 400$          | A          |
| <b>(RBSOA)</b> | Clamped Inductive Load                                    | @ $V_{CE} \leq V_{CES}$ |            |
| $t_{sc}$       | $V_{GE} = 15V$ , $V_{CE} = 360V$ , $T_J = 150^\circ C$    | 10                      | $\mu s$    |
| <b>(SCSOA)</b> | $R_G = 10\Omega$ , Non Repetitive                         |                         |            |
| $P_C$          | $T_C = 25^\circ C$  | 520                     | W          |
| $T_J$          |   | -55 ... +150            | $^\circ C$ |
| $T_{JM}$       |   | 150                     | $^\circ C$ |
| $T_{stg}$      |   | -55 ... +150            | $^\circ C$ |
| $T_L$          | Maximum Lead Temperature for Soldering                    | 300                     | $^\circ C$ |
| $T_{SOLD}$     | 1.6 mm (0.062 in.) from Case for 10                       | 260                     | $^\circ C$ |
| $V_{ISOL}$     | 50/60Hz, 1 minute   | 2500                    | V~         |
| $F_C$          | Mounting Force  | 50..200/11..45          | N/lb.      |
| <b>Weight</b>  |   | 8                       | g          |


 G = Gate                      E = Emitter  
 C = Collector

**Features**

- Silicon Chip on Direct-Copper Bond (DCB) Substrate
- Isolated Mounting Surface
- 2500V~ Electrical Isolation
- Optimized for Low Conduction and Switching Losses
- Avalanche Rated
- Short Circuit Capability
- Very High Current Capability
- Square RBSOA

**Advantages**

- High Power Density
- Low Gate Drive Requirement

**Applications**

- Power Inverters
- UPS
- Motor Drives
- SMPS
- PFC Circuits
- Battery Chargers
- Welding Machines
- Lamp Ballasts

| Symbol        | Test Conditions<br>( $T_J = 25^\circ C$ , Unless Otherwise Specified) | Characteristic Values |              |                    |
|---------------|---|-----------------------|--------------|--------------------|
|               |   | Min.                  | Typ.         | Max.               |
| $BV_{CES}$    | $I_C = 250\mu A$ , $V_{GE} = 0V$                                      | 600                   |              | V                  |
| $V_{GE(th)}$  | $I_C = 250\mu A$ , $V_{CE} = V_{GE}$                                  | 3.5                   |              | 6.0 V              |
| $I_{CES}$     | $V_{CE} = V_{CES}$ , $V_{GE} = 0V$<br>Note 2, $T_J = 150^\circ C$     |                       |              | 50 $\mu A$<br>3 mA |
| $I_{GES}$     | $V_{CE} = 0V$ , $V_{GE} = \pm 20V$                                    |                       |              | $\pm 200$ nA       |
| $V_{CE(sat)}$ | $I_C = 100A$ , $V_{GE} = 15V$ , Note 1<br>$T_J = 150^\circ C$         |                       | 1.40<br>1.58 | V<br>V             |

| Symbol Test Conditions<br>( $T_J = 25^\circ\text{C}$ Unless Otherwise Specified) |  | Characteristic Values |                         |         |
|--|--|-----------------------|-------------------------|---------|
|  |  | Min.                  | Typ.                    | Max.    |
| $g_{fs}$   | $I_C = 60\text{A}, V_{CE} = 10\text{V}$ , Note 1   | 27                    | 45                      | S       |
| $C_{ies}$  | $V_{CE} = 25\text{V}, V_{GE} = 0\text{V}, f = 1\text{MHz}$   |                       | 9970                    | pF      |
| $C_{oes}$  |  |                       | 570                     | pF      |
| $C_{res}$  |  |                       | 183                     | pF      |
| $Q_{g(on)}$  | $I_C = 200\text{A}, V_{GE} = 15\text{V}, V_{CE} = 0.5 \cdot V_{CES}$   |                       | 315                     | nC      |
| $Q_{ge}$   |  |                       | 98                      | nC      |
| $Q_{gc}$   |  |                       | 130                     | nC      |
| $t_{d(on)}$  | <b>Inductive load, <math>T_J = 25^\circ\text{C}</math></b><br>$I_C = 100\text{A}, V_{GE} = 15\text{V}$<br>$V_{CE} = 360\text{V}, R_G = 1\Omega$<br>Note 3  |                       | 48                      | ns      |
| $t_{ri}$   |  |                       | 100                     | ns      |
| $E_{on}$   |  |                       | 2.85                    | mJ      |
| $t_{d(off)}$   |  |                       | 160                     | ns      |
| $t_{fi}$   |  |                       | 110                     | ns      |
| $E_{off}$  |  |                       | 2.90                    | 4.40 mJ |
| $t_{d(on)}$  | <b>Inductive load, <math>T_J = 150^\circ\text{C}</math></b><br>$I_C = 100\text{A}, V_{GE} = 15\text{V}$<br>$V_{CE} = 360\text{V}, R_G = 1\Omega$<br>Note 3 |                       | 46                      | ns      |
| $t_{ri}$   |  |                       | 94                      | ns      |
| $E_{on}$   |  |                       | 4.40                    | mJ      |
| $t_{d(off)}$   |  |                       | 180                     | ns      |
| $t_{fi}$   |  |                       | 215                     | ns      |
| $E_{off}$  |  |                       | 3.45                    | mJ      |
| $R_{thJC}$   |  |                       | 0.24 $^\circ\text{C/W}$ |         |
| $R_{thCS}$   |  | 0.05                  | $^\circ\text{C/W}$      |         |

**Reverse Diode (FRED)**

| Symbol Test Conditions<br>( $T_J = 25^\circ\text{C}$ Unless Otherwise Specified) |  | Characteristic Values |                         |       |
|--|--|-----------------------|-------------------------|-------|
|  |  | Min.                  | Typ.                    | Max.  |
| $V_F$  | $I_F = 100\text{A}, V_{GE} = 0\text{V}$ , Note 1<br>$T_J = 150^\circ\text{C}$  |                       | 2.3                     | 2.5 V |
| $I_{RM}$   | $I_F = 100\text{A}, V_{GE} = 0\text{V}, T_J = 150^\circ\text{C}$<br>$-di_F/dt = 1500\text{A}/\mu\text{s}, V_R = 300\text{V}$ |                       | 95                      | A     |
| $t_{rr}$   |  |                       | 100                     | ns    |
| $R_{thJC}$   |  |                       | 0.83 $^\circ\text{C/W}$ |       |

**Notes:**

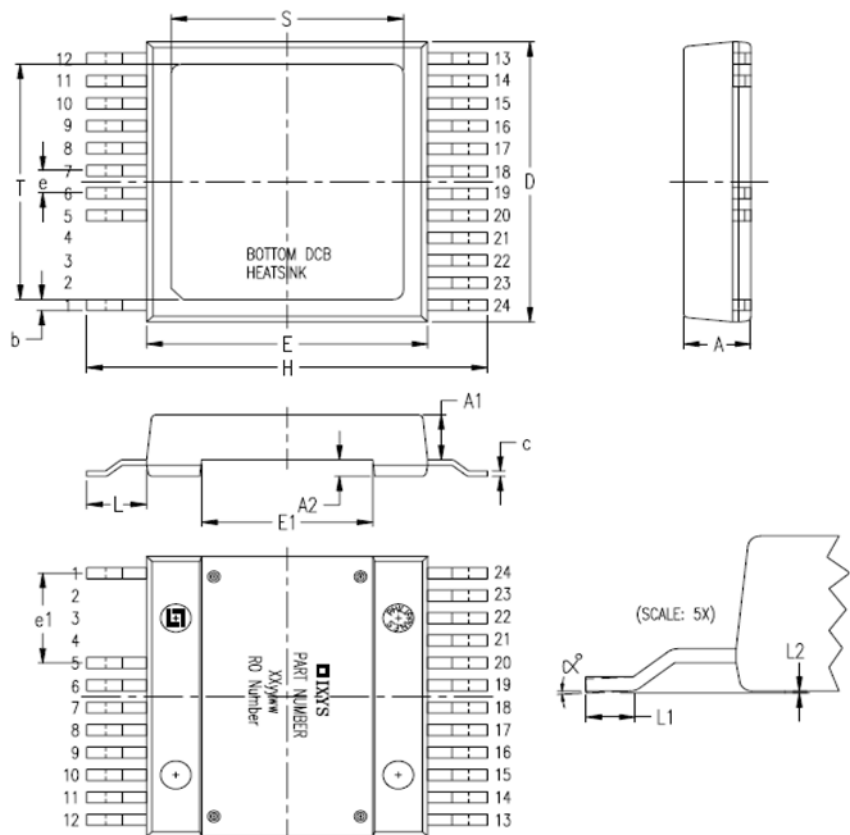
1. Pulse test,  $t \leq 300\mu\text{s}$ , duty cycle,  $d \leq 2\%$ .
2. Part must be heatsunk for high-temp  $I_{CES}$  measurement.
3. Switching times & energy losses may increase for higher  $V_{CE}(\text{Clamp})$ ,  $T_J$  or  $R_G$ .

**PRELIMINARY TECHNICAL INFORMATION**

The product presented herein is under development. The Technical Specifications offered are derived from a subjective evaluation of the design, based upon prior knowledge and experience, and constitute a "considered reflection" of the anticipated result. IXYS reserves the right to change limits, test conditions, and dimensions without notice.

IXYS Reserves the Right to Change Limits, Test Conditions, and Dimensions.

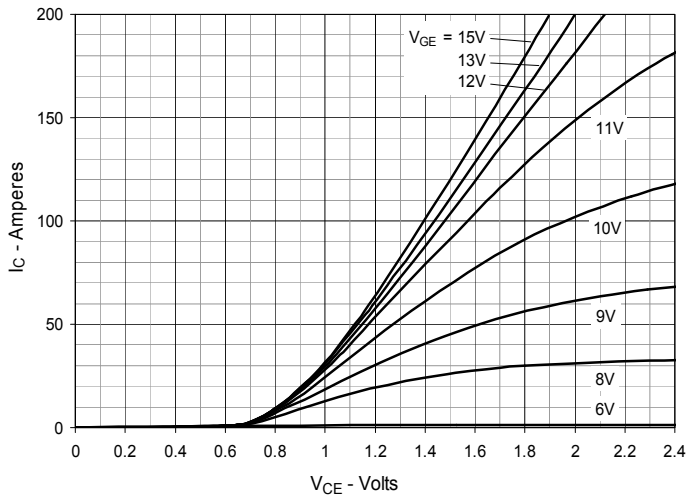
|   |           |           |           |           |              |              |              |              |              |             |
|---|-----------|-----------|-----------|-----------|--------------|--------------|--------------|--------------|--------------|-------------|
| IXYS MOSFETs and IGBTs are covered            | 4,835,592 | 4,931,844 | 5,049,961 | 5,237,481 | 6,162,665    | 6,404,065 B1 | 6,683,344    | 6,727,585    | 7,005,734 B2 | 7,157,338B2 |
| by one or more of the following U.S. patents: | 4,860,072 | 5,017,508 | 5,063,307 | 5,381,025 | 6,259,123 B1 | 6,534,343    | 6,710,405 B2 | 6,759,692    | 7,063,975 B2 |             |
|   | 4,881,106 | 5,034,796 | 5,187,117 | 5,486,715 | 6,306,728 B1 | 6,583,505    | 6,710,463    | 6,771,478 B2 | 7,071,537    |             |



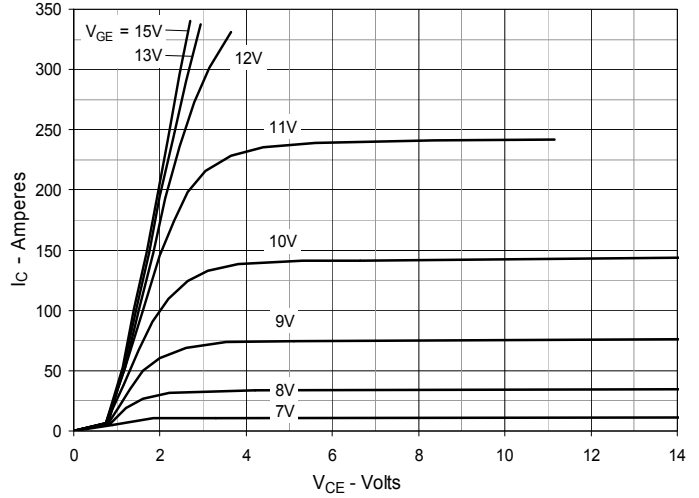
| SYM | INCHES   |       | MILLIMETERS |       |
|-----|----------|-------|-------------|-------|
|     | MIN      | MAX   | MIN         | MAX   |
| A   | .209     | .224  | 5.30        | 5.70  |
| A1  | .154     | .161  | 3.90        | 4.10  |
| A2  | .055     | .063  | 1.40        | 1.60  |
| b   | .035     | .045  | 0.90        | 1.15  |
| c   | .018     | .026  | 0.45        | 0.65  |
| D   | .976     | .994  | 24.80       | 25.25 |
| E   | .898     | .915  | 22.80       | 23.25 |
| E1  | .543     | .559  | 13.80       | 14.20 |
| e   | .079 BSC |       | 2.00 BSC    |       |
| e1  | .315 BSC |       | 8.00 BSC    |       |
| H   | 1.272    | 1.311 | 32.30       | 33.30 |
| L   | .181     | .209  | 4.60        | 5.30  |
| L1  | .051     | .067  | 1.30        | 1.70  |
| L2  | .000     | .006  | 0.00        | 0.15  |
| S   | .736     | .760  | 18.70       | 19.30 |
| T   | .815     | .839  | 20.70       | 21.30 |
| α   | 0        | 4°    | 0           | 4°    |

**PIN: 1 = Gate**  
**5-12 = Emitter**  
**13-24 = Collector**

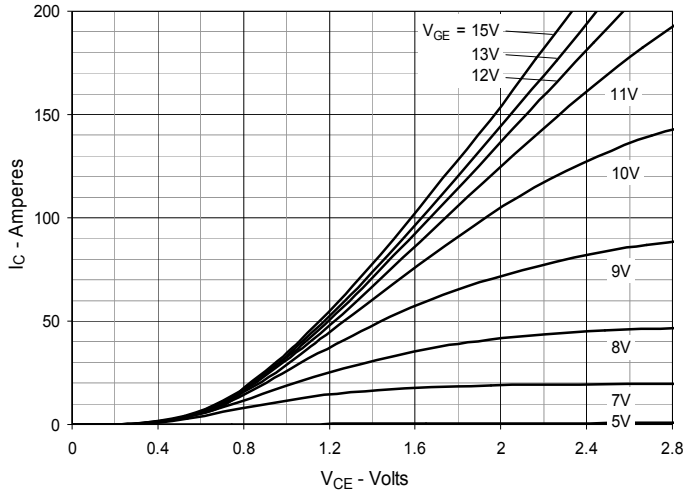
**Fig. 1. Output Characteristics @  $T_J = 25^\circ\text{C}$**



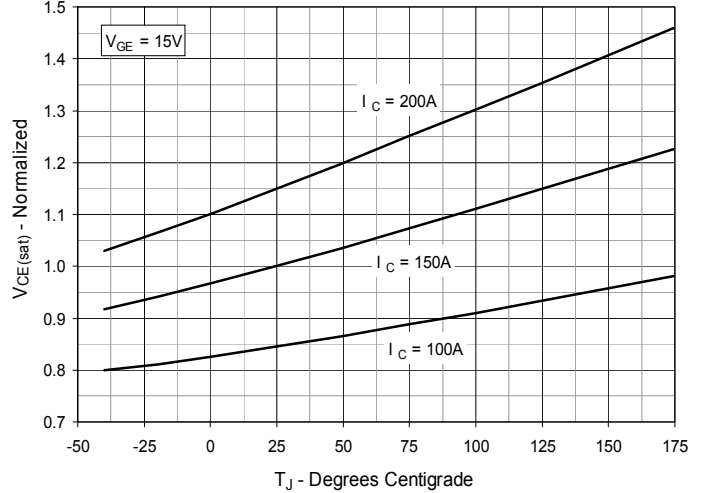
**Fig. 2. Extended Output Characteristics @  $T_J = 25^\circ\text{C}$**



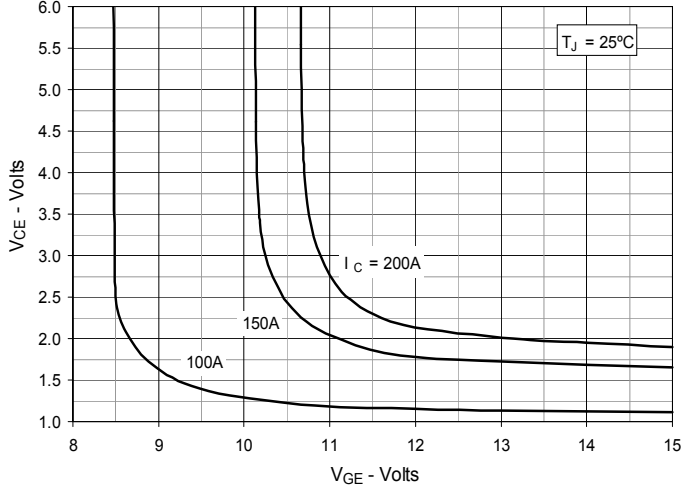
**Fig. 3. Output Characteristics @  $T_J = 150^\circ\text{C}$**



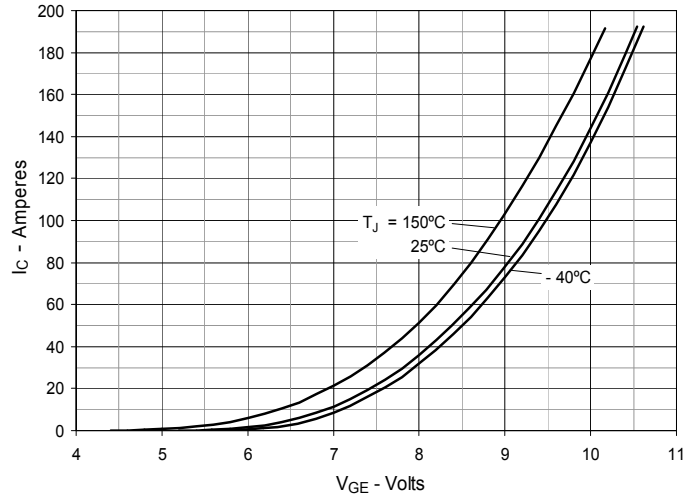
**Fig. 4. Dependence of  $V_{CE(sat)}$  on Junction Temperature**



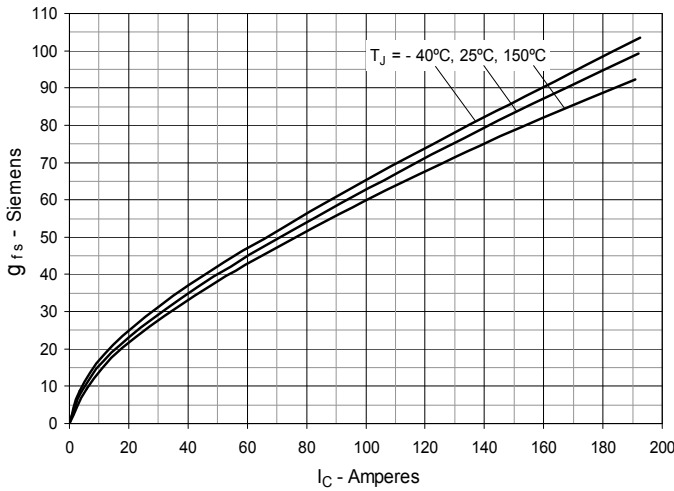
**Fig. 5. Collector-to-Emitter Voltage vs. Gate-to-Emitter Voltage**



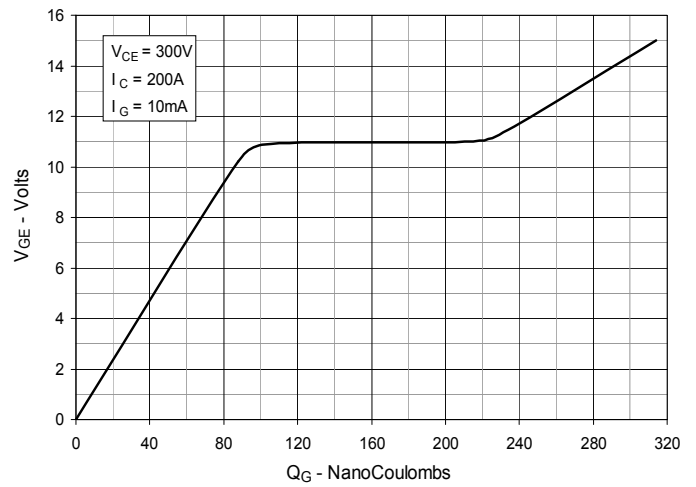
**Fig. 6. Input Admittance**



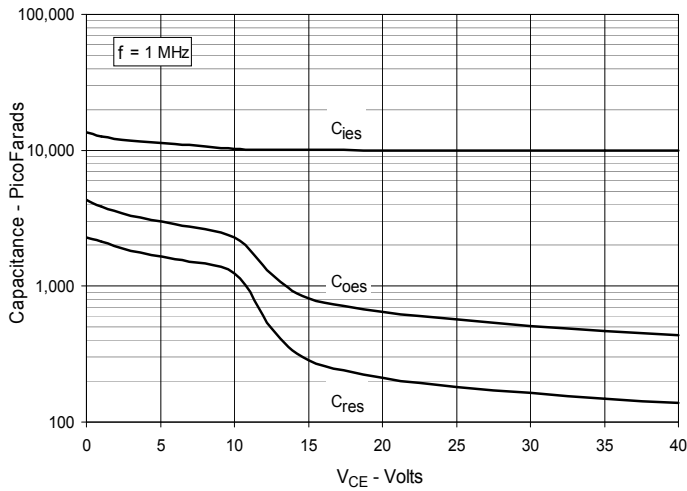
**Fig. 7. Transconductance**



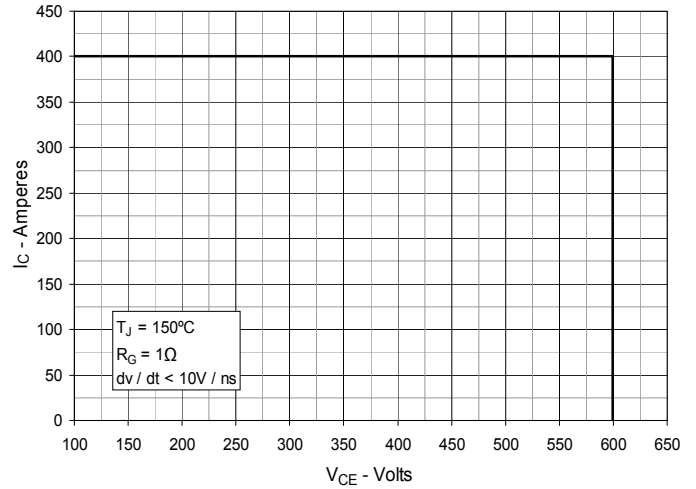
**Fig. 8. Gate Charge**



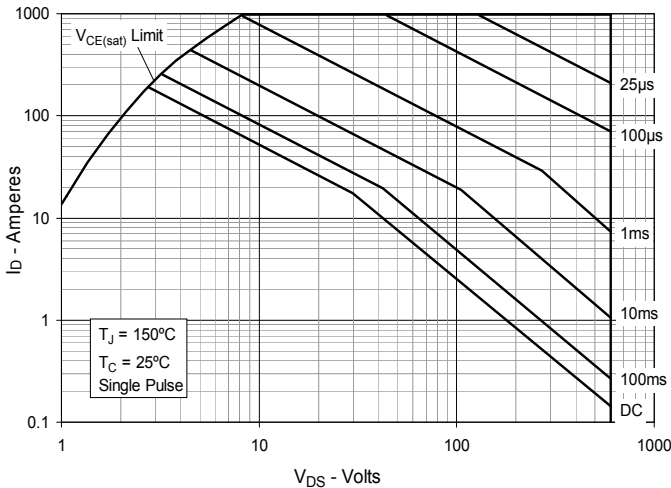
**Fig. 9. Capacitance**



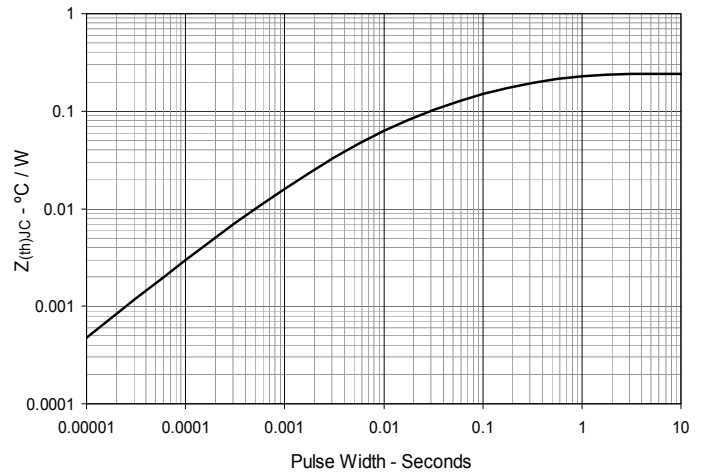
**Fig. 10. Reverse-Bias Safe Operating Area**



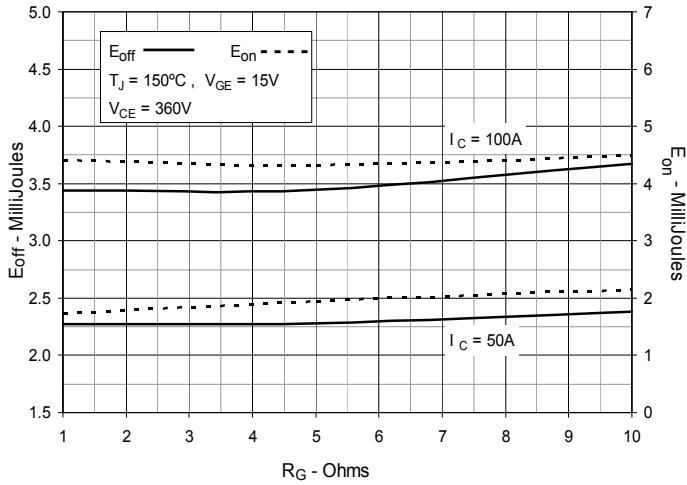
**Fig. 11. Forward-Bias Safe Operating Area**



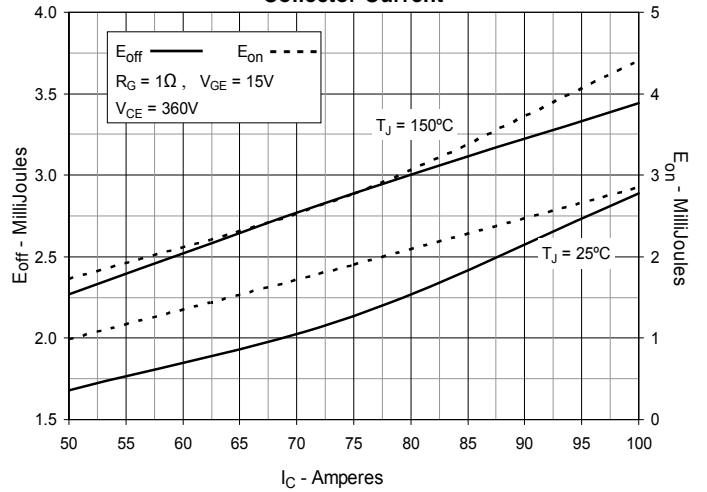
**Fig. 12. Maximum Transient Thermal Impedance**



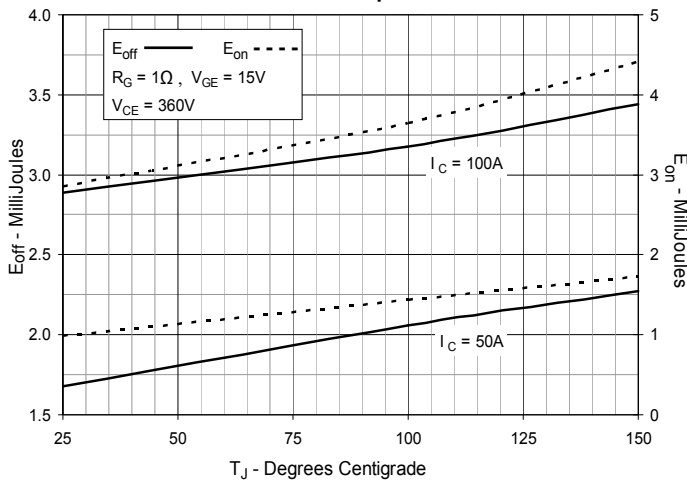
**Fig. 13. Inductive Switching Energy Loss vs. Gate Resistance**



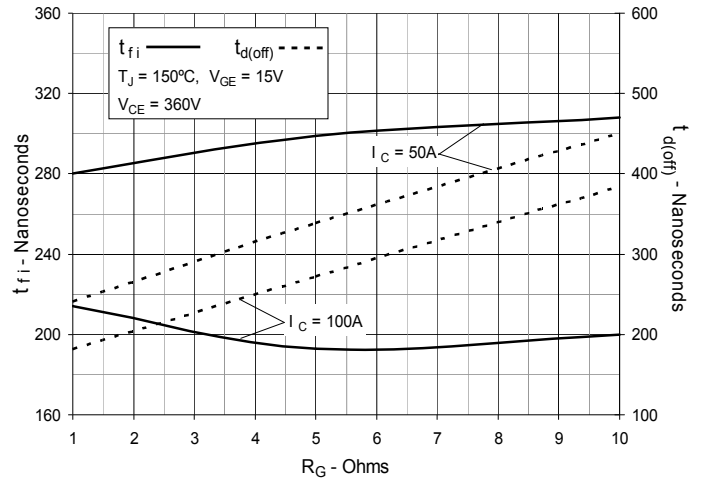
**Fig. 14. Inductive Switching Energy Loss vs. Collector Current**



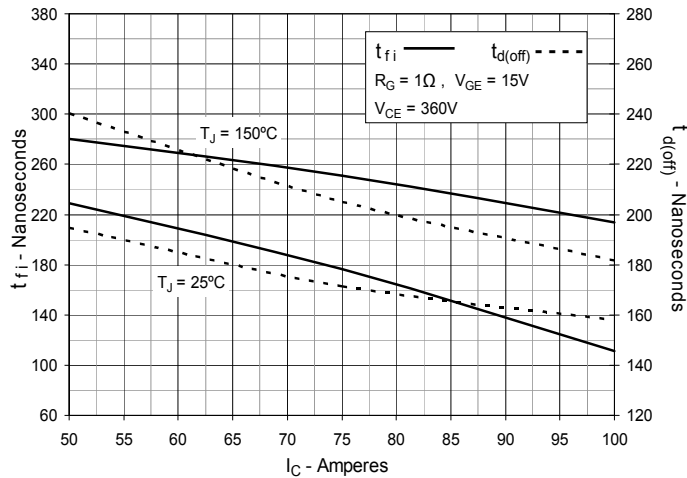
**Fig. 15. Inductive Switching Energy Loss vs. Junction Temperature**



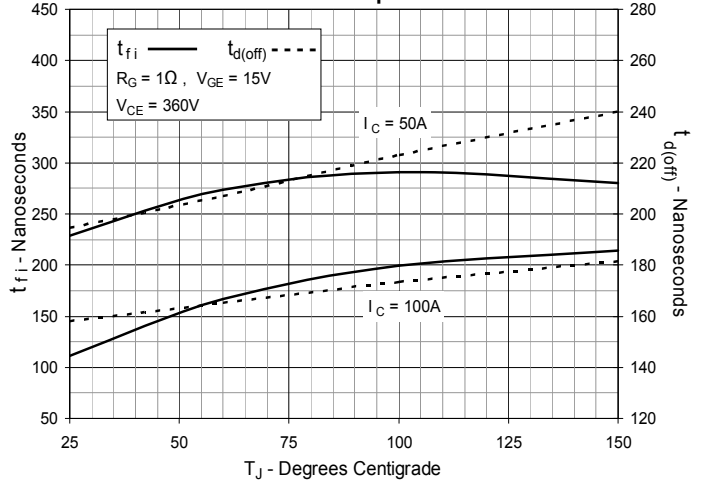
**Fig. 16. Inductive Turn-off Switching Times vs. Gate Resistance**



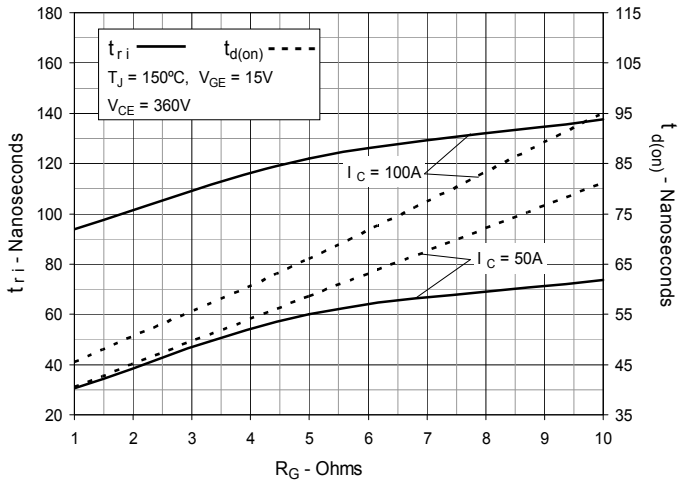
**Fig. 17. Inductive Turn-off Switching Times vs. Collector Current**



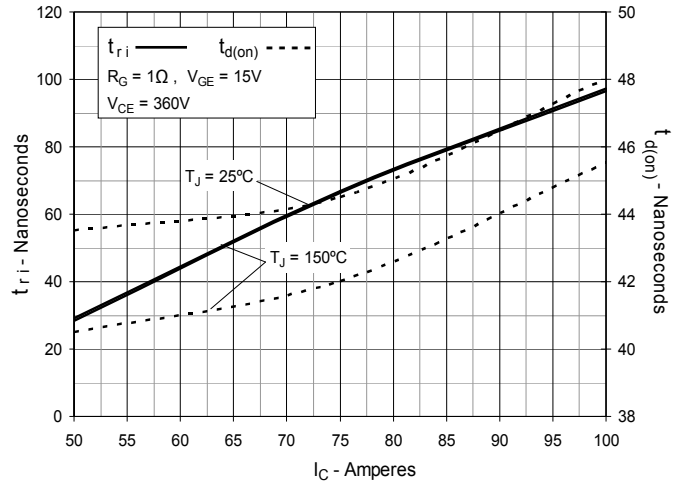
**Fig. 18. Inductive Turn-off Switching Times vs. Junction Temperature**



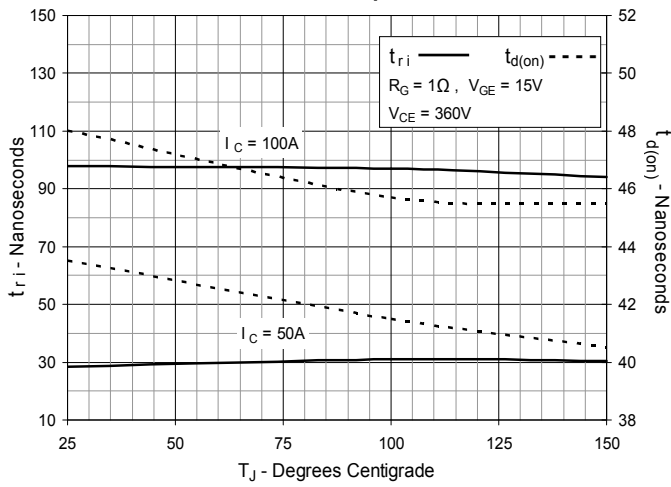
**Fig. 19. Inductive Turn-on Switching Times vs. Gate Resistance**



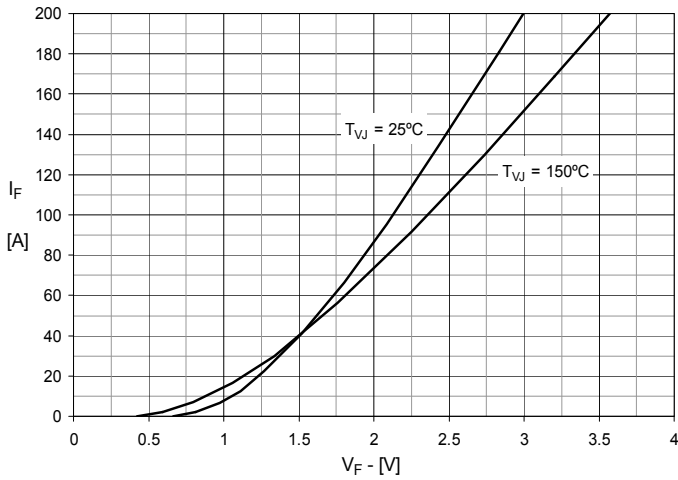
**Fig. 20. Inductive Turn-on Switching Times vs. Collector Current**



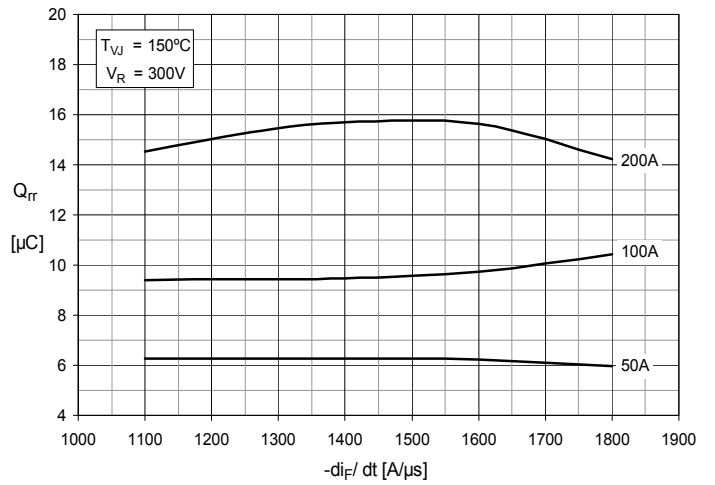
**Fig. 21. Inductive Turn-on Switching Times vs. Junction Temperature**



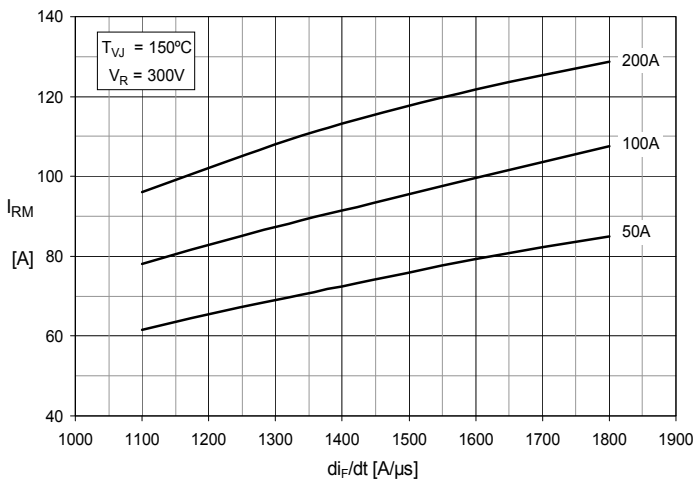
**Fig. 22. Typ. Forward characteristics**



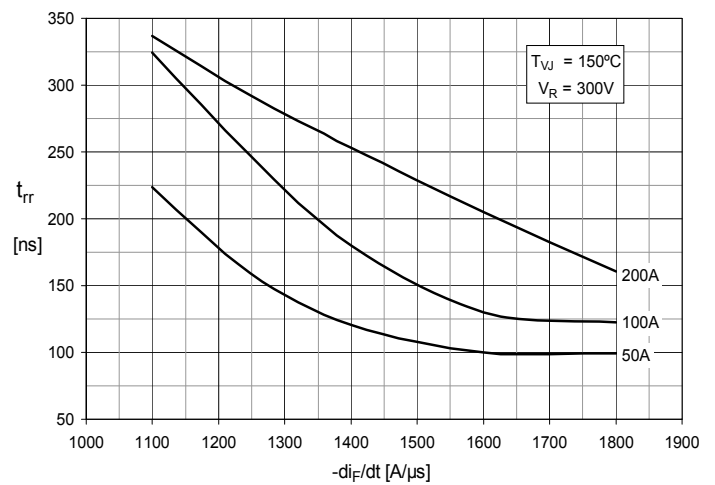
**Fig. 23. Typ. Reverse Recovery Charge  $Q_{rr}$  vs.  $-di_F/dt$**



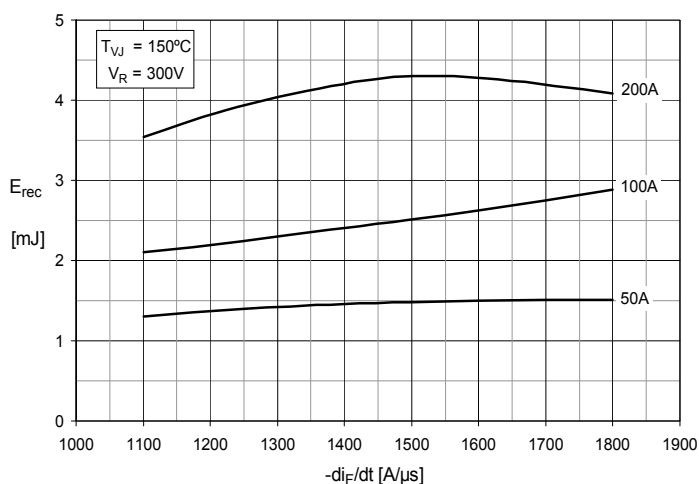
**Fig. 24. Typ. Peak Reverse Current  $I_{RM}$  vs.  $-di_F/dt$**



**Fig. 25. Typ. Recovery Time  $t_{rr}$  vs.  $-di_F/dt$**



**Fig. 26. Typ. Recovery Energy  $E_{rec}$  vs.  $-di_F/dt$**





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